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Nanomanufacturing — Key control characteristics

Part 3-3: Luminescent nanomaterials — Determination of fluorescence lifetime of semiconductor quantum dots using time correlated single photon counting (TCSPC)

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National foreword

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NANOMANUFACTURING – KEY CONTROL CHARACTERISTICS –

Part 3-3: Luminescent nanomaterials – Determination of fluorescence lifetime of semiconductor quantum dots using time correlated single photon counting (TCSPC)

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IEC TS 62607-3-3, which is a Technical Specification, has been prepared by IEC technical committee 113: Nanotechnology standardization for electrotechnical products and systems.

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Enquiry draft	Report on voting
113/490/DTS	113/529/RVDTS

Full information on the voting for the approval of this Technical Specification can be found in the report on voting indicated in the above table.

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The committee has decided that the contents of this document will remain unchanged until the stability date indicated on the IEC website under "http://webstore.iec.ch" in the data related to the specific document. At this date, the document will be

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